

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/501,985	AIRIAU ET AL.	
Examiner H. T. Le			Art Unit 1773	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,786,294	07-1998	Sachtler et al.	502/349
*	B	US-5,958,367	09-1999	Ying et al.	423/701
*	C	US-6,027,706	02-2000	Pinnavaia et al.	423/600
*	D	US-6,623,858	09-2003	Yabe et al.	428/403
*	E	US-6,656,588	12-2003	Laine et al.	428/402
*	F	US-6,866,925	03-2005	Chane-Ching, Jean-Yves	428/304.4
*	G	US-6,955,855	10-2005	Naasani, Imad	428/403
*	H	US-7,025,943	04-2006	Zhou et al.	423/263
*	I	US-7,182,929	02-2007	Singhal et al.	423/592.1
*	J	US-2004/0192947	09-2004	Chane-Ching et al.	549/533
*	K	US-2005/0239634	10-2005	Ying et al.	502/064
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2003-238118	08-2003	JAPAN	TATSUO	
	O	FR-2836067 A1	08-2003	FRANCE	CHANE	
	P	FR-2838427 A1	10-2003	FRANCE	CHANE	
	Q	FR-2819432 A1	01-2001	FRANCE	CHANE-CHING	
	R	WO-96/31434	10-1996	WIPO	YING	
	S	WO-02/057183 A1	07-2002	WIPO	CHANE-CHING	
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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